



Manipulating the distribution of electric field intensity to effectively enhance the spatial and spectral fluorescence intensity of fluorescent nanodiamonds

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- 1) Additional discussions about the enhanced effect of Al/SiO₂ nanocavity system for the fluorescence intensity of FNDs.

Thank you very much for your precious comments.

According to our previous study¹, the relationship between the optical admittance and the amplitude of surface electric-field ($E_{surface}$) can be obtained through the transfer matrix method.¹ The following equation S1 can express the surface electrical field ($E_{surface}$) on the of nanocavity:

$$E_{surface} = \sqrt{\frac{4}{(\alpha + 1)^2 + \beta^2}} \quad (S1)$$

where α and β are the real and imaginary parts of the optical admittance of the thin-film assembly. Therefore, the maximum $E_{surface}$ could be up to 2 when both α and β approached zero. In our previous

study, through well controlled the thickness of the dielectric SiO₂ film, the maximum $E_{surface}$ on the surface of two dimensional (2D) materials can be enhanced.²

In this study, we used the concept to design an Al/SiO₂ nanocavity and systematic interrogated the $E_{surface}$ effect of the nanocavity for the FNDs by both thin-film interference and 3D-FDTD methods. The spherical shape of FNDs unlike 2D materials, the $E_{surface}$ would perform a non-uniform distribution inside the FND. Moreover, due to the surface of the FND generally lacked NV⁻ centers, we should control and manipulate the distributions of the electric-field intensities within FNDs by tuning the thickness of the capping SiO₂ layer of the Al/SiO₂ nanocavities to effectively enhance the fluorescence intensity of the FNDs.

Note and References:

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